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# **TRNG (True Random Number Generator) Method** Using Visible Spectrum for Secure **Communication on 5G Network**

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**ABSTRACT** The key point of cryptography is cryptographic algorithms and keys. The random number generator is used to generate seeds and keys randomly in many cryptographic systems. For this reason, it is essential to use keys to encrypt and decrypt the transferring information, and the security of these keys is closely related to the security of 5G network. We propose a true random number generator (TRNG) method in this paper, and are using visible spectrum for noise source. We consider that if the cryptography system utilizes data of visible spectrum using the proposed TRNG, and the TRNG generates random numbers with high entropy.

**INDEX TERMS** 5G security, random number, true random number generator, visible spectrum, random number generation, cryptography, mobile communication.

## I. INTRODUCTION

CRYPTOGRAPHIC system is a system to prevent the leakage and manipulation of the transferred information by an attacker, and the key point of cryptography is cryptographic algorithms and keys. The key is usually generated based on the seed, and the seed must be random. For this reason, it is essential to use keys to encrypt and decrypt the transferred information. Moreover, these random values are utilized not only for keys, but also for various applications. For example, there application are that generation of padding bits, generation of masking to prevent DPA (Differential Power Analysis), hiding operation, generation of OTP (One Time Password), lottery, and statistical simulation [1]. Especially, in 5G network, various information is transmitted between communication entities, and cryptography is required to transmit the information securely. Hence, it is essential to use a key for encryption and decryption of transferring data, and security of these keys is closely related to the security of 5G network.

There are two types of random number generators: PRNG (Pseudo Random Number Generator) and TRNG (True Random Number Generator). PRNG intentionally generates a random number, not a complete random number, and the number is usually generated by a software way. TRNG, on the other hand, generates a true random number and is generated primarily by hardware way [2]. For this reason, the random number generated by TRNG is hard to predict because TRNG is generated based on a physical source that is difficult to predict a random value. Therefore, the random number generated from TRNG is a safe method because it is difficult to generate the same value. However, PRNG is a deterministic system so the generated random number can be guaranteed to be safe when the entropy of initial value has high entropy, but it is impossible to generate the complete random number in the deterministic system. Hence, there is a problem that the attacker conjectures the same key derived from same random number by generating the same initial value such as seed. In addition, it is impossible to generate a complete random number using only mathematical algorithms.

Therefore, this paper proposes a method of TRNG and uses visible spectrum as a noise source. Visible spectrums have difference values even at the same position and the same time, and the range of values is relatively wide. Namely, it is impossible to generate a random value that cannot be predicted even if the environment is the same. In particular, proposed TRNG can provide more secure communication because the TRNG can generate a random value and utilize it as a key for each entity, for example a base band and a station, in 5G network.

This paper is organized as in the following. In section 2, we describe related work, including types of random numbers, generation methods, and existing random number generators. In section 3, we introduce proposed TRNG, including concept, system model, and experiment results. Conclusion and references close the paper.

# **II. RELATED WORKS**

# A. TYPES OF RANDOM NUMBERS AND GENERATION METHODS

Random number can be generated in various ways, usually with PRNG and TRNG. The difference between PRNG and TRNG is deterministic, PRNG is a deterministic random number generator, and TRNG is a non-deterministic random number generator.

PRNG generates a long-length random number using algorithms based on a short initial value. The generated random number is called the pseudo random number, which has excellent statistical property [3]. However, the disadvantage is that it is difficult to generate a random initial value and it has a problem with a limited period [4]. For this reason, it is impossible to generate complete random number by using the deterministic random number generator. These generators are LFSR (Linear Feedback Shift Register), LCG (Linear Congruential Generator), multiplication system, and so on [5]–[7].

TRNG generates random number using the randomness of physical phenomena. The generated random number is called a true random number, which is unpredictable, unbiased, and independent. However, the disadvantage is that it is not enough flexibility because it is implemented in hardware, and verification of randomness is required because the randomness is changed according to environment.

The generating method of above random number is classified into two ways; software method and hardware method. A software method is generating random number based on information of a computer, and mainly utilizes information generated during a user-computer interaction. Such information includes network traffic information, hard disk operation information, and so on. Therefore, it is possible to generate a random number based on such information; there is a problem that the same random number is generated when the same environment is configured. For example, when an attacker manipulates information depends on a computer platform such as process, the same random number is generated. This means that the same key can be generated based on the generated same random number. Unlike the software method, the hardware method generates random number based on unpredictable physical phenomena and has been proposed to solve the drawbacks of the software methods [8]-[10]. This method is needed an extra device to collect the random number from physical phenomena, and usually utilizes noise. However, there are disadvantages that the extra device is required and it is difficult to implement.

#### TABLE 1. Classification of random number generation methods.

Category	Generation methods	Description
Classical	- Throwing a coin	- Cause of occurrence: probability
method	- Throwing a dice	
White	- Thermal noise	- Cause of occurrence: noise affected by
noise	- Shot noise	the environment
method		- Generation material: register, small
		AC voltage, polarity semiconductor
Jittered	- jitter	- Cause of occurrence: Unstable of
oscillator	- clock	oscillator
method		<ul> <li>Generation way: change the fast</li> </ul>
		oscillator signal to the slower oscillator
		signal
Unstable state	- Connecting inverter input and	- Cause of occurrence: Unstable state of digital circuit
method	output	- Generation way: Switching from a
	- Disconnecting	metastable state to a bitstable state in an
	inverter input and	actual circuit
	output	
Chaotic	- Non-linear shape	- Cause of occurrence: Chaotic signal
signal	of the natural	with aperiodic irregularity
method	world	- Generation way: Sampling values
		from chaotic circuits

# **B. EXISTING RANDOM NUMBER GENERATORS**

1) GENERATION METHODS OF RANDOM NUMBER

The random number generation methods are classified into five methods as shown in Table 1, a classical method, a white noise method, a jittered oscillator, an unstable state, and a chaotic signal.

The classical method is to generate random number based on probability, and there are throwing a coin and throwing a dice. This method is generated values unexpectedly such as coin and dice. However, this method needs a lot of manpower due to manually generation, so it cannot use actual system [4].

White noise method utilizes noise generated in the supply portion of the power supply to generate random number, using resister, small AC voltage, and polarity semiconductor. Noise is generated by thermal noise and shot noise, and these noises are outpoured week signals [11]–[14]. Therefore, the random number is generated based on the amplified signal because the generated value can be biased when sampling the signal. Generated random number varies irregularly depending on the environment in which when circuit is designed, the error of the machine, and the environment in which when circuit is running.

Jittered oscillator method utilizes the instability of the oscillator to generate random number [14], [15]. Way to generate noise is to affect from a fast oscillator signal to a slower oscillator signal, and the signal output from the oscillator is waved in this case and is called jitter. The reason for this phenomenon is that although the oscillator generates signal with a constant value of 0 and 1, but the part changing from 0 to 1 and the part changing from 1 to 0 are not accurate due to the influence of the process and the circuit driving environment, so this causes an error. Therefore, the fast oscillator signal is sampled with D flip-flop using a slower clock

signal to generate a random number with high entropy [11], [13], [15]. Moreover, there is a method of changing the signal of fast oscillator and processing xor operation with several fast oscillators to increase entropy [16]–[19]. Thus, the generated value is influenced by the surrounding environment, so the value cannot be predicted.

Unstable state method utilizes the phenomenon that the output of the circuit changes unstably to 0 or 1 to generate a random number. Digital circuit has only bistable state, which is 0 or 1 state. However, in an actual circuit, there is a metastable state which is unstable state, not 0 or 1. Therefore, the output is waved by the noise between 0 and 1, and the output value is determined 0 or 1 randomly when disconnect in a metastable state. This means that the generated information at that time of disconnection is determined by the noise, so it is impossible to predict the generated value [20]–[24].

Chaotic signal utilized the sampling value from the chaotic signal, which is a nonlinear characteristic of a natural world, to analog signal [25], [26]. Even if an ideal system is designed for a chaotic system, the actual system has an error, and such error as noise is sufficient to be used as a random number. For this reason, the generated random number is irregular and difficult to predict. Therefore, if all the conditions such as the initial value and the parameter are not completely same, a completely different value is generated. This means that this method is effective for generating the random number. However, there is a disadvantage that the generated value is limited to a specific range [25], [27].

# 2) THE SOURCE OF RANDOM NUMBER GENERATOR

The source of random number generator is classified into six sources as shown in Table 2, electrical and electronic circuits, external and auxiliary devices, system information, chaotic signal, natural world system, and others.

Electrical and electronic circuits are classified as semiconductor device, super-luminescent LED, and flip-flop. Semiconductor device is highly affected by the environment, and various noise caused by this environment can be used as a source for a ransom number. These noises include thermal noise, flicker noise, shot noise, avalanche noise, generation/recombination noise, and noise diode/resistance. As with semiconductor device, super luminescent LED emits noise, which is used as the random number source. Flip-flop has metastability state, so noise causes from the state.

External and auxiliary devices are classified as a monitor, disk, MIC, TV/radio, laser, and digital camera. Monitor utilizes noise emitted from a radiation monitor with RS-232 output as a random number source. Disk generates the random number based on air convection inside the disk drive due to rotation speed, space, air flow by heat condition, movement of head and support, etc. MIC utilizes noise of collected signal from MIC or the difference between two microphone signals as the source. TV/radio utilizes noise, including TV/radio broadcasting signal as the source. Laser utilizes the phase noise of the laser and digital camera utilizes noise, including image collected from camera. TABLE 2. Classification of the random number generator sources.

Category	Source	Description
Electrical	Semiconductor	- thermal noise
and	device [28, 29,	- Flicker noise
electronic	30, 31, 32, 33, 34, 35, 36, 37]	- shot noise
circuits	34, 35, 36, 37]	- Avalanche noise - diffusion noise
		- generation/recombination noise
		- noise diode/resistance
	Super-luminesc	- Noise from LED
	ent LED [38]	
	Flip-flop [38]	- Metastability of flip-flop
External	Monitor	- Radiation monitor with RS-232 output
and	Disk	- Air convection inside the disk drive due
auxiliary		to rotation speed, space, air flow by heat
devices		condition, movement of head and support
		etc.
	MIC	- Noise from MIC
	(microphone)	- Difference between two microphone
	T V/Radio	signals - Broadcasting signal T V/radio
	Laser [38, 39]	- The phase noise of the laser
	Digital camera [40, 41, 42]	- Image with noise from digital camera
System	Network and	- Information about network traffic and
informati	process	running processes
on	I/O device	- I/O completion timing and statistic
	Time	- System date and time
	RAM [38]	- Block RAM write conflict
Chaotic	Laser [43]	- Chaotic laser
signal	Chaos system	- Well-known system: Lorenz system, th
	[44, 45, 46, 47,	Logistic map, the Henonmap, the Rossle
	48, 49, 50, 51,	system, and the double rod pendulum
	52, 53, 54]	- Dynamical system: Chua's system, the
NT-4 1	T :-1.4	Tent map, and the Sawtooth map
Natural world	Light	- Photon polarization detection
system	Amount of	- Amount of insolation of measured time
55 Stern	insolation [40,	
	41,42] Atmospheric	- Atmospheric flow of measured time
	dynamics [40,	- Atmospherie now of measured time
	41, 42]	
	Radioactive	- the decay of radioactive nucleus
	material [55]	· · · · · · · · · · · · · · · · · · ·
	Single photon	- Irregular split time and arrival time
	[56, 57]	
	Natural	- The naturally emitted noise signal
0.1	emission [58]	
Others	Publication	- Information on publications such as
	Decendin -	newspaper, magazine, and book
	Recording media	- Information recorded on CD ROMs,
	meula	Audio CDs, and tapes

System information utilizes unpredictable information during system running as a random number source, and this source is classified into the network and process, I/O device, time, and RAM. Network and process utilize the information about network traffic and running processes as a random number source, and I/O device utilizes I/O completion timing and statistic as the source. Time generated random number based on the system date and time from when the system is booted, and RAM utilizes write conflict caused by block RAM as the source.

Chaotic signal is classified into the laser and chaotic system. Laser utilizes the chaotic signal from the laser as a

random number. Chaotic system utilizes information collected from well-known chaotic and dynamical system as the random number.

Natural world system is classified as light, amount of insolation, atmospheric dynamics, radioactive material, single photon, and natural emission. Light utilizes noise emitted from the feature that the light is randomly polarized, and amount of insolation utilizes irregular amount of insolation of measured time as the random number. Atmospheric dynamics utilizes the atmospheric flow of measured time as the random number, and radioactive material utilizes the decay of radioactive nucleus. Single photon generated random number based on irregular split time and arrival time, and natural emission utilized noise signal emitted naturally as the source of the random number. Others are that publication source utilizes information on publications such as newspaper, magazine, and book, and recording media source utilizes information recorded on CD ROMs, Audio CDs, and tapes.

Moreover, the following articles have recently been studied. The fingerprint is collected every time, noise occurs due to the environment, the collecting way, and contact area, and this noise is utilized as a random number [59]. A new method using image collected from camera has been studied, this method after sequential two images are subtracted, if the result is a positive number, it is determined to be 1, and if the result if negative, it is determined to be 0. [60]. In the method using the Moire fringe, a difference in lattice frequency occurs in a state in which lattices having two similar spatial phases are overlapped, and the low-frequency component, among these, is called the Moire interference fringe. These fringes are irregular, so these are used as random number [61].

#### **III. PROPOSED TRNG**

## A. CONCEPT

Although there are various random number generators as described above, there is a problem that these generators utilize a limited and insufficient data as a random number and a source. We consider that one of the important factors is to generate random numbers based on sufficient data from the source. Therefore, proposed TRNG generates random numbers from sufficient information and its noise, and use visible spectrum that can generate more noise to do this.

Visible spectrum is generally the region of electromagnetic waves in the rage of 400nm to 700nm, as shown in figure 1, and this area is called spectrum [62]. A spectrum has information of more than 300 electromagnetic waves, and the range of the information also has a wide range of values corresponding to the range of electromagnetic waves. Therefore, the visible spectrum contains a lot of information that can be used as a random number, so this is suitable for use as the random number because the information is originated from electromagnetic waves.

Detailed process and procedure for acquiring visible spectrum are shown in Fig. 2. The inputted illumination is

Color	Violet	Blue	Green	Yellow	Orange	Red
Wavelength	380-410 nm	415-495 nm	495-570 nm	570-590 nm	590-620 nm	620-750 nm
Frequency	668-789 THz	606-668 THz	526-606 THz	508-526 THz	484-508 THz	400-484 THz
Photon energy	2.75-3.26 ev	2.50-2.75 ev	2.17-2.50 ev	2.10-2.17 ev	2.00-2.10 ev	1.65-2.00 ev

#### FIGURE 1. The visible spectrum.

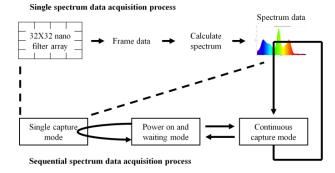


FIGURE 2. Spectrum data acquisition process.

TABLE 3. Part of the collected visible spectrum.

Wavelength	400	401	 729	730
Spectrum-1	0.0924933	0.10209	 0.0608392	0.0585175
Spectrum-2	0.108507	0.118519	 0.0648131	0.0609462
			 	•••
Spectrum- 999	0.196799	0.193059	 0.141342	0.134564
Spectrum- 1000	0.193488	0.188438	 0.156311	0.157035

converted into frame data by 32X32 nano filter array, and the data is calculated to represent the wavelength as a spectrum. Through this process, spectrum data corresponding to inputted illumination is acquired. This process extracts a single spectrum, which operates in a single capture mode. To generate continuous random numbers, spectrum data must be continuously collected, so the spectrum data is collected the number of times in continuous mode when specific number of times is set. In this mode, parameters such as shutter speed, average, and number of times required for acquisition are set.

As shown in Figs. 1 and 2, visible spectrum has various information in wavelength, frequency, and photon energy. In this paper, we collect data of visible spectrum based on wavelength, and some of the results are shown in Table 3 and Fig. 3.

As shown in Fig. 3, the collected spectrum has not distributed pattern. In order to improve the randomness of the collected data, we take two decimal places, and the distribution is shown in Fig. 4.

As shown in Fig. 4, the two decimal places are processed as data to generate a random number, and the data are appropriately distributed.

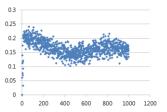


FIGURE 3. Collected spectrum data.

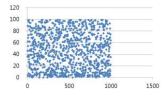


FIGURE 4. Distribution of two decimal places of spectrum data.

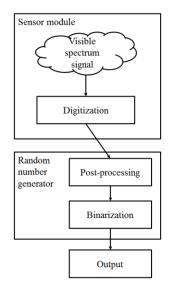


FIGURE 5. TRNG configuration (model).

## **B. SYSTEM MODEL**

The proposed TRNG model is shown in Fig. 5, and the module consists of a collection module, a generation module, and an output module based on NIST 800-90b [3].

The collection module is a sensor module. This module consists of a sensor that collects data of the visible spectrum and an interface to transfer collected information to a computer. Among them, the sensor collecting visible spectrum information is a noise source, and the sensor converts the analog signal to digital information and transmits it. The collected information is passed to a generation module, which performs post-processing to generate a random number. The post-processing process increases the distribution as described in Section III-A, reduces the correlation between each spectrum, so the result improves the randomness. The post-processing result is binarized to measure the entropy, so the result value has 0 or 1. The binarized result from the generation module transfers to the output module, the module saves all collected results as a file in a format for measuring the entropy.

Based on the system model, the procedure for acquiring spectrum data is described as follows:

*Step 1:* The sensor module collects the analog signal of illumination from a 32X32 nano filter array. This signal is not a digital signal, but an analog signal with a lot of noise.

*Step 2:* In the sensor module, the analog signal collected in step 1 is converted into frame data, which is a digital signal. After calculating the spectrum based on the converted digital signal, the calculation result is composed of spectrum data. This is the digitization step.

*Step 3:* When spectrum data is collected, the data is performed a post-processing process for using random number by random number generator. The post-processing process enhances the distribution of the collected spectrum data, reduces the correlation between the spectrum data and improves the randomness. In this paper, we utilize two decimal places as random numbers to improve the randomness of collected data.

*Step 4:* In this paper, we decide the size of the generated random number to be 1 bit, and perform binarization with 0 and 1 based on the result processed in step 3. The result of the binarization is transferred to the output module and stored as a file. Finally, a random number having a size of 1 bit is generated using the stored file.

## C. EXPERIMENT RESULT

In this paper, we collected 1,000 spectrums for the experiment, and collected the output results through processing described in section 3.2. The data collected in one spectrum collects a total of 331 spectrum data from 400nm to 730nm in wavelength, so total number of collected data is 331,000 because total 1,000 spectrums are collected.

There are various methods to measure the randomness of collected random data. In this paper, we use the entropy estimation tool provided by NIST. NIST has released a tool for measuring the entropy of generated random numbers, and now 800-90b has been released [3]. 800-90b estimates the randomness by other estimation methods according to the properties of the random number, and the estimation methods are classified into independent and identically distributed (IID) and non-IID. IID estimates when the generated random number is independent, while non-IID estimates when the generated random number is not independent. In this paper, we estimate the entropy by non-IID estimation method because the collected random number is based on the continuously collected spectrums. Entropy was estimated based on four consecutive spectrum data, and the results are shown in Table 4 and Fig. 6.

Non-IID means that there is a dependency between data. Namely, it is possible to predict the value that will appear later through the previous value. Therefore, various entropy estimation methods are needed for dependent values having sequence. The methods provided by NIST obtain the probability of correctly estimating next value using the dependencies between the data in various ways, and the entropy is calculated according to the probability obtained.

Estimat	ion method	TEST 1	TEST 2	TEST 3	TEST 4	NIST sample
dRunning	Most Common	P(max): 0.502621	P(max): 0.502756	P(max): 0.503695	P(max): 0.504939	P(max): 0.501721
entropic	Value	Min-entropy: 0.992457	Min-entropy: 0.992043	Min-entropy: 0.989377	Min-entropy: 0.985819	Min-entropy: 0.995043
statistic	Collision	P(max): 0.604492	P(max): 0.604004	P(max): 0.600586	P(max): 0.606201	P(max): 0.535156
statistic		Min-entropy: 0.726204	Min-entropy: 0.72737	Min-entropy: 0.735557	Min-entropy: 0.722131	Min-entropy: 0.901968
	Markov	P(max): 6.02073e-39	P(max): 6.32058e-39	P(max): 7.14917e-39	P(max): 9.97228e-39	P(max): 4.00013e-39
		Min-entropy: 0.991916	Min-entropy: 0.991368	Min-entropy: 0.98998	Min-entropy: 0.986229	Min-entropy: 0.996525
	Compression	P(max): 0.553284	P(max): 0.552856	P(max): 0.552307	P(max): 0.554565	P(max): 0.5
		Min-entropy: 0.853909	Min-entropy: 0.855023	Min-entropy: 0.856457	Min-entropy: 0.85057	Min-entropy: 1
	t-Tuple	P(max): 0.609642	P(max): 0.586789	P(max): 0.603412	P(max): 0.59119	P(max): 0.529343
		Min-entropy: 0.713966	Min-entropy: 0.769086	Min-entropy: 0.728786	Min-entropy: 0.758306	Min-entropy: 0.917726
	LRS	P(max): 0.520513	P(max): 0.517699	P(max): 0.573474	P(max): 0.537049	P(max): 0.503651
		Min-entropy: 0.941995	Min-entropy: 0.949815	Min-entropy: 0.8022	Min-entropy: 0.896874	Min-entropy: 0.989503
Running	MultiMCW	P(max): 0.556115	P(max): 0.50115	P(max): 0.516113	P(max): 0.526367	P(max): 0.501051
predictor	Prediction	Min-entropy: 0.846544	Min-entropy: 0.996684	Min-entropy: 0.95424	Min-entropy: 0.925859	Min-entropy: 0.996972
predictor	Lag Prediction	P(max): 0.503077	P(max): 0.501833	P(max): 0.501747	P(max): 0.502816	P(max): 0.500592
		Min-entropy: 0.991149	Min-entropy: 0.99472	Min-entropy: 0.994969	Min-entropy: 0.991897	Min-entropy: 0.998291
	MultiMMC	P(max): 0.578522	P(max): 0.579763	P(max): 0.58071	P(max): 0.582543	P(max): 0.501159
	Prediction	Min-entropy: 0.789556	Min-entropy: 0.786466	Min-entropy: 0.784111	Min-entropy: 0.779563	Min-entropy: 0.99666
	LZ78Y	P(max): 0.568014	P(max): 0.502777	P(max): 0.542969	P(max): 0.503899	P(max): 0.501024
	Prediction	Min-entropy: 0.816001	Min-entropy: 0.99201	Min-entropy: 0.881059	Min-entropy: 0.988792	Min-entropy: 0.99705
Min	-entropy	0.713966	- •	0.728786	0.722131	0.901968

#### TABLE 4. Min-entropy of first estimation result.

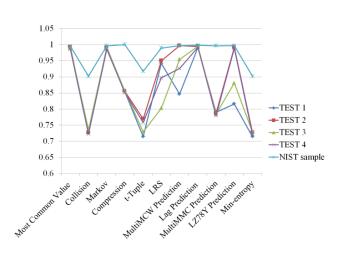


FIGURE 6. First estimation result.

The performance of TRNG is estimated by the calculated entropy. NIST recommends the following ten entropy estimation methods:

The Most Common Value Estimate: Calculate the entropy using the ratio of the most frequently appearing values from the input dataset.

The Collision Estimate: If the collision is an arbitrary repetitive value, the probability of the most frequently appearing output value is estimated based on the time until the collision occurs. When the collision time is longer, the entropy is calculated the high value.

The Markov Estimate: The min-entropy is calculated by measuring the dependency between successive values from the input dataset.

The Compression Estimate: The entropy of the dataset is calculated based on how much the dataset can be compressed.

The t-Tuple Estimate: The entropy is calculated per sample based on the frequency of the t-tuple appearing in the input dataset.

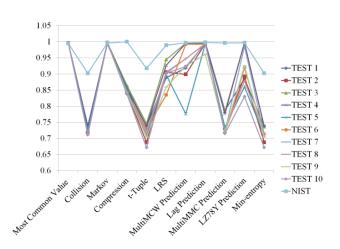
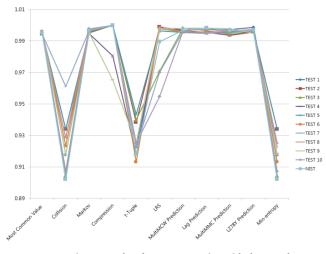
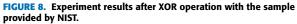


FIGURE 7. Results of a second experiment based on 1,000,000 data.





The Longest Repeated Substring (LRS) Estimate: The collision entropy of the source is calculated based on the number Estimation method

Estimat	ion method	TEST 1	TEST 2	TEST 3	TEST 4	TEST 5
dRunning	Most Common	P(max): 0. 501446	P(max): 0. 50124	P(max): 0. 501545	P(max): 0. 501238	P(max): 0. 501515
entropic statistic	Value Collision	Min-entropy: 0.995833 P(max): 0. 599121	Min-entropy: 0. 996426 P(max): 0. 60791	Min-entropy: 0. 99555 P(max): 0. 600098	Min-entropy: 0. 996432 P(max): 0. 599609	Min-entropy: 0. 995635 P(max): 0. 60498
statistic		Min-entropy: 0. 73908	Min-entropy: 0.71807	Min-entropy: 0. 736731	Min-entropy: 0. 737905	Min-entropy: 0.72504
	Markov	P(max): 4.9635e-39 Min-entropy: 0.994092	P(max): 3.90025e-39 Min-entropy: 0.99681	P(max): 3.70529e-39 Min-entropy: 0.997388	P(max): 3.70032e-39 Min-entropy: 0.997403	P(max): 4.33277e-39 Min-entropy: 0.995624
	Compression	P(max): 0. 554138	P(max): 0. 557373	P(max): 0. 549194	P(max): 0. 552002	P(max): 0. 553955
		Min-entropy: 0.851682	Min-entropy: 0.843285	Min-entropy: 0. 864611	Min-entropy: 0.857255	Min-entropy: 0. 852159
	t-Tuple	P(max): 0. 599777 Min-entropy: 0. 737502	P(max): 0. 620778 Min-entropy: 0. 68785	P(max): 0. 595942 Min-entropy: 0. 746757	P(max): 0. 591182 Min-entropy: 0. 738326	P(max): 0. 611909 Min-entropy: 0. 708611
	LRS	P(max): 0. 540092	P(max): 0. 533942	P(max): 0. 519429	P(max): 0. 525879	P(max): 0. 536994
		Min-entropy: 0.888724	Min-entropy: 0. 905244	Min-entropy: 0. 945001	Min-entropy: 0.927197	Min-entropy: 0.897022
Running	MultiMCW	P(max): 0. 528984	P(max): 0. 53879	P(max): 0. 501408	P(max): 0. 501671	P(max): 0. 583984
predictor	Prediction	Min-entropy: 0.918705	Min-entropy: 0. 8992205	Min-entropy: 0. 995942	Min-entropy: 0.995186	Min-entropy: 0. 775998
P	Lag Prediction	P(max): 0. 500772	P(max): 0. 501648	P(max): 0. 501372	P(max): 0. 501212	P(max): 0. 501953
		Min-entropy: 0.997773	Min-entropy: 0.995253	Min-entropy: 0.996047	Min-entropy: 0.996507	Min-entropy: 0.994375
	MultiMMC	P(max): 0. 579471	P(max): 0. 602237	P(max): 0. 581058	P(max): 0. 583623	P(max): 0. 601066
	Prediction	Min-entropy: 0.787191	Min-entropy: 0.731598	Min-entropy: 0. 783247	Min-entropy: 0. 776891	Min-entropy: 0. 734404
	LZ78Y	P(max): 0. 541219	P(max): 0. 53879	P(max): 0. 501036	P(max): 0. 501077	P(max): 0. 550781
Min-	Prediction entropy	Min-entropy: 0.885716 0.737502	Min-entropy: 0. 892205 0. 68785	Min-entropy: 0.997014 0.736731	Min-entropy: 0. 996894 0. 737905	Min-entropy: 0.860449 0.708611

#### TEST 6

TEST 7

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TEST 8

# TEST 9

TEST 10

dRunning	Most Common	P(max): 0. 501236	P(max): 0. 501388	P(max): 0. 501287	P(max): 0. 50136	P(max): 0. 501157
entropic	Value	Min-entropy: 0.996439	Min-entropy: 0.996	Min-entropy: 0. 996292	Min-entropy: 0. 996082	Min-entropy: 0. 996666
statistic	Collision	P(max): 0. 609863	P(max): 0. 609863	P(max): 0. 610352	P(max): 0. 610352	P(max): 0. 61084
statistic	Markov	Min-entropy: 0.713442 P(max): 3.58016e-39	Min-entropy: 0. 713442 P(max): 3.67234e-39	Min-entropy: 0. 712288 P(max): 3.82145e-39	Min-entropy: 0. 712288 P(max): 3.81106e-39	Min-entropy: 0. 71134 P(max): 3.73808e-39
		Min-entropy: 0.997775	Min-entropy: 0.997488	Min-entropy: 0. 99704	Min-entropy: 0. 99707	Min-entropy: 0.997288
	Compression	P(max): 0. 557373	P(max): 0. 55719	P(max): 0. 557861	P(max): 0. 557739	P(max): 0. 559509
	t-Tuple	Min-entropy: 0.843285 P(max): 0.603062	Min-entropy: 0. 843759 P(max): 0. 606176	Min-entropy: 0. 842022 P(max): 0. 609549	Min-entropy: 0. 842337 P(max): 0. 613911	Min-entropy: 0.837766 P(max): 0.627768
		Min-entropy: 0. 729621	Min-entropy: 0. 722192	Min-entropy: 0.714185	Min-entropy: 0. 703898	Min-entropy: 0. 671697
	LRS	P(max): 0. 560548	P(max): 0. 53501	P(max): 0. 533554	P(max): 0. 551183	P(max): 0. 535142
Running	MultiMCW	Min-entropy: 0.835091 P(max): 0.502643	Min-entropy: 0. 902361 P(max): 0. 518358	Min-entropy: 0. 906294 P(max): 0. 518358	Min-entropy: 0. 859396 P(max): 0. 526526	Min-entropy: 0. 902006 P(max): 0. 527344
predictor	Prediction	Min-entropy: 0.992394	Min-entropy: 0.94798	Min-entropy: 0.94798	Min-entropy: 0. 925422	Min-entropy: 0.923184
predictor	Lag Prediction	P(max): 0. 502643	P(max): 0. 501685	P(max): 0. 502081	P(max): 0. 513654	P(max): 0. 501646
	MultiMMC	Min-entropy: 0. 992394 P(max): 0. 60773	Min-entropy: 0. 995147 P(max): 0. 606887	Min-entropy: 0. 994008 P(max): 0. 606433	Min-entropy: 0.96113 P(max): 0.606995	Min-entropy: 0. 995258 P(max): 0. 60897
	Prediction	Min-entropy: 0. 718498	Min-entropy: 0.7205	Min-entropy: 0.72158	Min-entropy: 0. 720244	Min-entropy: 0.715556
	LZ78Y	P(max): 0. 528984	P(max): 0. 504886	P(max): 0. 543387	P(max): 0. 526526	P(max): 0. 5625
	Prediction	Min-entropy: 0.918705	Min-entropy: 0.985972	Min-entropy: 0.879947	Min-entropy: 0. 925422	Min-entropy: 0.830075
Min	-entropy	0.713442	0.713442	0.712288	0.703898	0.671697

of substrings that are repeated within the input dataset. This is a complementary estimation method that the size of the tuple can adjust when the size of the tuple is too long in the T-tuple estimate.

The Multi Most Common in Window Prediction Estimate: Based on the last w output, the next output is predicted, and the most common sample value is predicted. This method is designed for cases when the most common value changes over time.

*The Lag Prediction Estimate:* The entropy is calculated by obtaining the probability of predicting the next output based on the specified lag.

The Multi MMC Prediction Estimate: This constructs Multiple Markov Model with Counting (MMC). The entropy is calculated to predict the most frequently observed transitions from current output by observing the transition frequency of successive next outputs from one output.

*The LZ78Y Prediction Estimate:* This is used a method of adding a string to a dictionary based on LZ78 code. Predictor adds the new string to the dictionary until the string reaches

the maximum capacity of the dictionary. The entropy of the prediction success probability is calculated by using a dictionary to predict the next value.

The Multi Most Common in Window Prediction Estimate, The Lag Prediction Estimate, and The Multi MMC Prediction Estimate are calculated the entropy using a predictor selected within the highest probability of prediction success among several subpredictors. Otherwise, The LZ78Y Prediction Estimate is calculated as a probability to correctly predict the next value using values in the dictionary.

NIST recommends estimating entropy based on 1,000,000 data. However, the data collected from one test were 331,000, so the entropy was estimated based on insufficient data. Therefore, we estimate the entropy based on collected 1,000,000 data, the result is shown in Table 5 and Fig. 7.

As shown in Fig. 6, three experiment results have lower entropy than the sample provided by NIST. The reason is that the collected random number is not generated with high entropy having a certain probability, but has low entropy because the data is generated according to the visible

# TABLE 6. Experiment results after XOR operation with the sample provided by NIST.

Estimat	ion method	TEST 1	TEST 2	TEST 3	TEST 4	TEST 5
dRunning	Most Common	P(max): 0. 501343	P(max): 0. 501783	P(max): 0. 50183	P(max): 0. 501953	P(max): 0. 501697
entropic	Value	Min-entropy: 0.99613	Min-entropy: 0.994865	Min-entropy: 0. 994729	Min-entropy: 0.994376	Min-entropy: 0.995112
statistic	Collision	P(max): 0. 529297	P(max): 0. 523438	P(max): 0. 53418	P(max): 0. 525391	P(max): 0. 523438
		Min-entropy: 0. 917851	Min-entropy: 0. 933911	Min-entropy: 0. 904603	Min-entropy: 0. 928538	Min-entropy: 0.933911
	Markov	P(max): 3.71261e-39	P(max): 4.49904e-39	P(max): 4.32946e-39	P(max): 4.70339e-39	P(max): 4.12048e-39
	C	Min-entropy: 0. 997365	Min-entropy: 0.9952	Min-entropy: 0. 995633	Min-entropy: 0. 994699	Min-entropy: 0. 99619
	Compression	P(max): 0. 5	P(max): 0. 5	P(max): 0. 5	P(max): 0. 506836	P(max): 0. 5
	t Tuels	Min-entropy: 1 P(max): 0. 527557	Min-entropy: 1 P(max): 0, 52187	Min-entropy: 1 P(max): 0, 521265	Min-entropy: 0. 980409 P(max): 0. 529343	Min-entropy: 1 P(max): 0, 520025
	t-Tuple	Min-entropy: 0. 922601	Min-entropy: 0. 938238	Min-entropy: 0. 939911	Min-entropy: 0. 917726	Min-entropy: 0. 94334
	LRS	P(max): 0.500408	P(max): 0.50039	P(max): 0.510206	P(max): 0.500434	P(max): 0.501251
	LIKS	Min-entropy: 0. 998824	Min-entropy: 0. 998874	Min-entropy: 0. 970847	Min-entropy: 0. 998747	Min-entropy: 0. 99639:
Running	MultiMCW	P(max): 0. 501079	P(max): 0.501194	P(max): 0.500588	P(max): 0.501355	P(max): 0.501576
predictor	Prediction	Min-entropy: 0. 996891	Min-entropy: 0. 99656	Min-entropy: 0. 998303	Min-entropy: 0. 996097	Min-entropy: 0. 995461
predictor	Lag Prediction	P(max): 0.500944	P(max): 0.501568	P(max): 0. 501205	P(max): 0. 501783	P(max): 0. 501787
		Min-entropy: 0.99728	Min-entropy: 0. 995484	Min-entropy: 0. 996529	Min-entropy: 0. 994866	Min-entropy: 0.994854
	MultiMMC	P(max): 0.500929	P(max): 0.502208	P(max): 0.502017	P(max): 0.501359	P(max): 0.501436
	Prediction	Min-entropy: 0.997322	Min-entropy: 0. 993643	Min-entropy: 0.994192	Min-entropy: 0. 996084	Min-entropy: 0.995863
	LZ78Y	P(max): 0. 50047	P(max): 0. 501519	P(max): 0. 501358	P(max): 0. 501597	P(max): 0. 501334
	Prediction	Min-entropy: 0. 998643	Min-entropy: 0. 995625	Min-entropy: 0. 996088	Min-entropy: 0.995401	Min-entropy: 0.996157
Min	-entropy	0.917851	0.933911	0.904603	0.917726	0.933911
Min		0.917851	0.933911	0.904603	0.917726	0.933911
		0.917851 TEST 6	0.933911 TEST 7	0.904603 TEST 8	0.917726 TEST 9	0.933911 TEST 10
Estimat	-entropy ion method Most Common					
Estimat dRunning	-entropy ion method Most Common Value	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877	TEST 7	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047
Estimat dRunning entropic	-entropy ion method Most Common	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203
Estimat dRunning entropic	-entropy ion method Most Common Value Collision	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851	TEST 10 P(max): 0.501372 Min-entropy: 0.996047 P(max): 0.533203 Min-entropy: 0.907243
	-entropy ion method Most Common Value	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907243 P(max): 3.61062e-39
Estimat dRunning entropic	-entropy ion method Most Common Value Collision Markov	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 997338	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 996661	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907675 P(max): 3.61062e-39 Min-entropy: 0. 997675
Estimat dRunning entropic	-entropy ion method Most Common Value Collision	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 99738 P(max): 0. 5	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 99661 P(max): 0. 5	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238 P(max): 0. 5	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907243 P(max): 3.61062e-39 Min-entropy: 0. 997679 P(max): 0. 5
Estimat dRunning entropic	-entropy ion method Most Common Value Collision Markov Compression	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 997338 P(max): 0. 5 Min-entropy: 1	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 996661 P(max): 0. 5 Min-entropy: 1	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 97238 P(max): 0. 5 Min-entropy: 1	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207 Min-entropy: 0. 965201	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907243 P(max): 3.61062e-39 Min-entropy: 0. 997679 P(max): 0. 5 Min-entropy: 1
Estimat dRunning entropic	-entropy ion method Most Common Value Collision Markov	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 997338 P(max): 0. 5 Min-entropy: 1 P(max): 0. 531042	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3. 95212e-39 Min-entropy: 0. 996661 P(max): 0. 5 Min-entropy: 1 P(max): 0. 527557	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207 Min-entropy: 0. 965201 P(max): 0. 526629	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907243 P(max): 3.61062e-39 Min-entropy: 0. 997675 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629
Estimat dRunning entropic	-entropy ion method Most Common Value Collision Markov Compression t-Tuple	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 997338 P(max): 0. 5 Min-entropy: 1 P(max): 0. 531042 Min-entropy: 0. 913101	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 996661 P(max): 0. 5 Min-entropy: 1 P(max): 0. 527557 Min-entropy: 0. 922601	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629 Min-entropy: 0. 925141	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207 Min-entropy: 0. 965201 P(max): 0. 526629 Min-entropy: 0. 925141	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907675 P(max): 3.61062e-39 Min-entropy: 0. 997675 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629 Min-entropy: 0. 925141
Estimat dRunning entropic	-entropy ion method Most Common Value Collision Markov Compression	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 97338 P(max): 0. 5 Min-entropy: 1 P(max): 0. 531042 Min-entropy: 0. 913101 P(max): 0. 500792	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 99661 P(max): 0. 5 Min-entropy: 1 P(max): 0. 527557 Min-entropy: 0. 922601 P(max): 0. 510478	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629 Min-entropy: 0. 925141 P(max): 0. 500274	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207 Min-entropy: 0. 965201 P(max): 0. 526629 Min-entropy: 0. 925141 P(max): 0. 500765	TEST 10 P(max): 0. 501372 Min-entropy: 0. 996047 P(max): 0. 533203 Min-entropy: 0. 907243 P(max): 3.61062e-39 Min-entropy: 0. 997679 P(max): 0. 5 Min-entropy: 1. 925141 P(max): 0. 515954
Estimat dRunning entropic statistic	-entropy ion method Most Common Value Collision Markov Compression t-Tuple LRS	TEST 6 P(max): 0. 501431 Min-entropy: 0. 995877 P(max): 0. 527344 Min-entropy: 0. 923184 P(max): 3.72164e-39 Min-entropy: 0. 997338 P(max): 0. 5 Min-entropy: 1 P(max): 0. 531042 Min-entropy: 0. 913101 P(max): 0. 500792 Min-entropy: 0. 997717	TEST 7 P(max): 0. 50196 Min-entropy: 0. 994356 P(max): 0. 513672 Min-entropy: 0. 961081 P(max): 3.95212e-39 Min-entropy: 0. 996661 P(max): 0. 5 Min-entropy: 1 P(max): 0. 527557 Min-entropy: 0. 922601 P(max): 0. 510478 Min-entropy: 0.97008	TEST 8 P(max): 0. 501595 Min-entropy: 0. 995405 P(max): 0. 525391 Min-entropy: 0. 928538 P(max): 3.7549e-39 Min-entropy: 0. 997238 P(max): 0. 5 Min-entropy: 1 P(max): 0. 526629 Min-entropy: 0. 925141 P(max): 0. 500274 Min-entropy: 0. 99921	TEST 9 P(max): 0. 501387 Min-entropy: 0. 996004 P(max): 0. 529297 Min-entropy: 0. 917851 P(max): 4.48173e-39 Min-entropy: 0. 995243 P(max): 0. 512207 Min-entropy: 0. 965201 P(max): 0. 526629 Min-entropy: 0. 925141 P(max): 0. 500765 Min-entropy: 0. 997794	TEST 10 P(max): 0.501372 Min-entropy: 0.996047 P(max): 0.533203 Min-entropy: 0.907243 P(max): 3.61062e-39 Min-entropy: 0.997675 P(max): 0.5 Min-entropy: 1 P(max): 0.526629 Min-entropy: 0.925141 P(max): 0.515954 Min-entropy: 0.954686
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#### TABLE 7. Comparison with existing random number generators.

Entropy source	Estimated	Sample	Entropy source	Reference
	entropy	Size		
Wireless (LQI)	0.47	8 bits	Wireless (LQI)	Hennebert et al. [63]
Accelerometer X	0.22	9 bits	Accelerometer X	Hennebert et al. [64]
Accelerometer Y	0.42	9 bits	Accelerometer Y	
Accelerometer Z	0.36	9 bits	Accelerometer Z	
Vibration sensor	0.17	16 bits	Vibration sensor	
Magnetic sensor	0.62	16 bits	Magnetic sensor	
GTX 690	0.50	4 bits	GTX 690	Yoo et al. [65]
GTX 780	0.60	4 bits	GTX 780	
Only visible spectrum	0.72	1 bit	Only visible spectrum	Our results
Visible spectrum with XOR operation	0.93	1 bit	Visible spectrum with XOR operation	

spectrum. Therefore, in order to improve the entropy higher, we estimate processed data that the operation result after

the XOR operation with the sample provided by NIST. The estimation results are shown in Table 6 and Fig. 8.

As a result, the entropy of the NIST sample is 0.901968, and the results of our three tests are 0.917851, 0.933911, and 0. 904603, respectively. This means that the entropy can be increased by performing the XOR operation based on the generated random number including the existing PRNG, rather than using the data of the visible spectrum independently. The increase rate of entropy was increased from 0.29% to 3.54% at maximum. Consequently, proposed TRNG can be expected to generate random numbers with high entropy.

Finally, we compare and evaluate proposed random number generator with existing random number generators, and the results are shown in Table 7 [63]–[65]. As a result, most existing generators have low entropy and the highest entropy is 0.62. However, the proposed generator has minimum entropy of 0.72 and a maximum of 0.93, which is increased from at least 86% to a maximum of 423%. This means that the proposed method is practically excellent.

## **IV. CONCLUSION**

In this paper, we proposed a TRNG using the visible spectrum as a source. The visible spectrum contains a lot of information that can be used as a random number. The spectrum includes a lot of noises because the information is originated from electromagnetic waves. The collected visible spectrum information performs post-processing. Through this process, generated random numbers are increasing the distribution, reducing the correlation between each spectrum and increasing the randomness. We collected 1,000 spectrums for the experiment and estimated the entropy using tool provided by NIST. As a result of the estimation, the data collected from one test were 331,000, so the entropy was estimated based on insufficient data, which has low entropy. The reason is that the collected random number is not generated with high entropy having a certain probability but has low entropy because the data is randomly generated according to the visible spectrum. Therefore, in order to increase the entropy, we estimated based on the operation result after the XOR operation with the sample provided by NIST. As a result, three test results increased the entropy. This means that the entropy can be increased by performing the XOR operation based on the generated random number including the existing PRNG, rather than using the data of the visible spectrum independently. Consequently, proposed TRNG can be expected to generate random numbers with high entropy.

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